

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination 10/693,177 KIRSCHNER ET AL.	
		Examiner Steven S. Paik	Art Unit 2876	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-4,780,599 A	10-1988	Baus, Heinz G.	235/383
*	B	US-5,463,209 A	10-1995	Figh et al.	235/383
*	C	US-5,652,421 A	07-1997	Veeneman et al.	235/381
*	D	US-5,822,216 A	10-1998	Satchell et al.	700/232
*	E	US-5,978,777 A	11-1999	Garnier, Dominique	705/27
*	F	US-6,078,928 A	06-2000	Schnase et al.	707/104.1
*	G	US-2003/0093538 A1	05-2003	Tsuchiuchi, Takayasu	709/229
*	H	US-2003/0227854 A1	12-2003	Weaver, Deirdre L.	369/75.1
*	I	US-6,758,398 B1	07-2004	Philyaw et al.	235/454
*	J	US-6,879,264 B2	04-2005	Hidaka et al.	340/825.19
*	K	US-7,024,453 B2	04-2006	Stern et al.	709/203
*	L	US-7,083,103 B2	08-2006	Hull, Mark D.	235/487
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.